

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	548	(marking near3 defect\$3)and (wafer\$1 or semiconductor\$1 or IC or intergrated adj circuit)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/11/14 14:24
L2	336	(marking near3 defect\$3)same(wafer\$1 or semiconductor\$1 or IC or intergrated adj circuit)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/11/14 14:24
L3	3	L2 same (photomask or reticle)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/11/14 14:25
L4	2	L3 and @ad<"20011116"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/11/14 14:28
L5	48	photomask\$3 near3 inspect\$3 same repair	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/11/14 14:28
L6	0	L5 same (photomask\$3 or reticle)same pattern same mark near3 installer	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/11/14 14:30
L7	2	L5 and (photomask\$3 or reticle)same pattern same mark near3 installer	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/11/14 14:30
L8	461	L5 same(photomask\$3 or reticle)same eliminat\$3 near3 defect\$3same finder near3 mark	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/11/14 14:32
L9	0	L5 same(photomask\$3 or reticle)same eliminat\$3 near3 defect\$3 same finder near3 mark	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/11/14 14:32
L10	2	L5 and(photomask\$3 or reticle)and eliminat\$3 near3 defect\$3 and finder near3 mark	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/11/14 14:32